

<b>Notice of References Cited</b>	Application/Control No. 10/560,001		Applicant(s)/Patent Under Reexamination TOMOZAWA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0168831 A1	11-2002	Miyasaka, Yoichi	438/396
*	C	US-6,494,567 B2	12-2002	Murai, Masami	347/71
*	D	US-6,624,458 B2	09-2003	Takamatsu et al.	257/295
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*	F	US-7,083,269 B2	08-2006	Murai, Masami	347/68
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	K	US-			
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cheng et al.: Thin Solid Films, Vol.385, Issues 1-2, April 2001, pp.5-10, Thickness-dependent microstructures and electrical properties of PZT films derived from sol-gel process
	V	Sumi et al.: Thin Solid Films, Vol.315, Issues 1-2, March 1998, pp.77-85: Effect of the annealing temperature on structural and piezoelectric properties of the sol-gel Pb(Zr 0.56Ti 0.44) 0.90 (Mg 1/3 Nb 2/3) 0.10 O3 films
	W	Barzegar: Study of Size (Aspect Ratio) Effect on Longitudinal Piezoelectric Coefficient Measured by Quasistatic Technique, 2002 IEEE Ultrasonics Symposium.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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